

SUBCLASS		ISSUE CLASSIFICATION		PATENT NUMBER	
013					
039					
CLASS					
SCANNED		O.P.E.		PATENT DATE	
09/784626		250		559.11 2372	
EXAMINER		ART UNIT		RECEIVED	
TITLE		CLASS		SUBCLASS	
APPLICANTS		CONT/PRIOR		ART UNIT	
Daniel Some Silviu Reinhorn Gilad Almogy					
BEST AVAILABLE COPY					
A laser scanning Wafer inspection using nonlinear optical Phenomena					

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